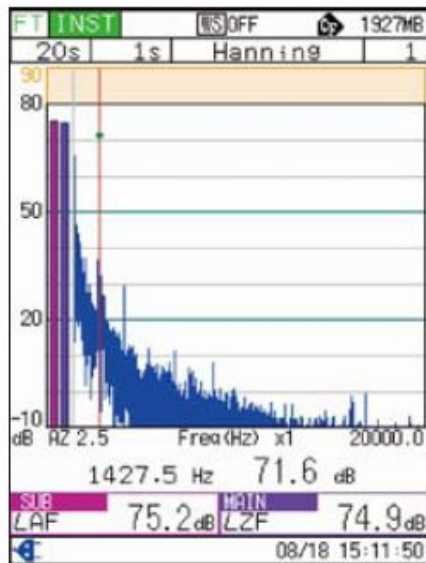




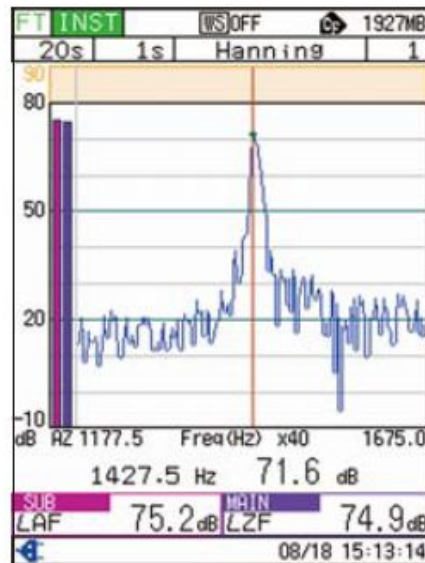
NX-28FT program card adds FFT analysis capability to NA-28.

- Analysis frequency range: 20 kHz (fixed)
- Number of analysis lines: 8,000 (fixed) (frame time 400 ms, frequency resolution 2.5 Hz)

FFT Analysis Card NX-28FT



Measurement screen (zoom factor x1)



Measurement screen (zoom factor x40)

Specifications

Standard compliance	ISO 1996-2: 2007 Annex C *1
Measurement mode (FFT mode)	Main channel all-pass value and FFT analysis Sub-channel all-pass value
Measurement items	Simultaneous measurement of INST and LIN or MAX Measurement time 1 to 999 seconds
Dynamic range	100 dB
Analysis frequency range	20 kHz (fixed)
Time window functions	Hanning, Rectangular
Number of spectrum lines	8,000 (fixed) (frame time 400 ms, frequency resolution 2.5 Hz)
Sampling frequency	48 kHz (fixed)
Display	
Measurement screen	Simultaneous display of FFT analysis result and all-pass level
Number of FFT display lines	200
Zoom ratio	x1, x2, x5, x10, x20, x40
Top list screen	List display of frequency and level values for top 20 lines, in descending order
Trigger	Controls start of measurement and memory store operation
Level trigger	Measurement starts when threshold level (selectable in 1 dB steps) is exceeded, and ends after preset measurement time has elapsed. Trigger source: main channel all-pass value only. Slope fixed to +.
External trigger	Measurement starts at falling edge of logic level signal supplied to trigger input
Store function	
Manual store	Stores measurement results.
Number of data sets	
CF card*2	Max. 20 store names, with up to 100 data sets each (Store to internal memory not supported)
Combination with NX-28WR	Allows waveform recording under measurements for LIN, MAX. Waveform data stored together with manual store data on CF card.

*1 Only frequency analysis is performed on unit. Tonal index calculation is performed on computer.

*2 Use only RION supplied cards for assured operation.